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### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Discontinued at Digi-Key
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	72MHz
Connectivity	I <sup>2</sup> C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	21
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 13x14b; D/A 4x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	24-SSOP (0.154", 3.90mm Width)
Supplier Device Package	24-QSOP
Purchase URL	<a href="https://www.e-xfl.com/product-detail/silicon-labs/efm8lb12f64e-a-qsop24">https://www.e-xfl.com/product-detail/silicon-labs/efm8lb12f64e-a-qsop24</a>

## 2. Ordering Information

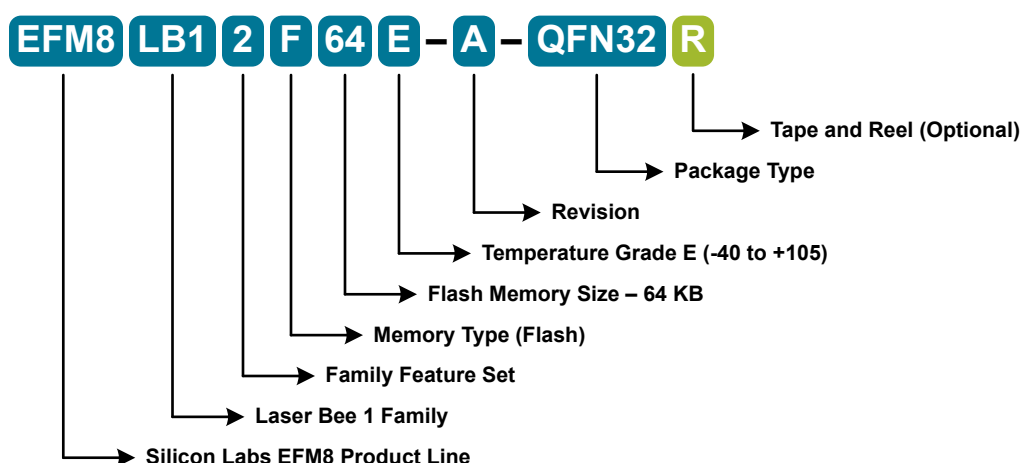


Figure 2.1. EFM8LB1 Part Numbering

All EFM8LB1 family members have the following features:

- CIP-51 Core running up to 72 MHz
- Three Internal Oscillators (72 MHz, 24.5 MHz and 80 kHz)
- SMBus
- I2C Slave
- SPI
- 2 UARTs
- 6-Channel Programmable Counter Array (PWM, Clock Generation, Capture/Compare)
- Six 16-bit Timers
- Four Configurable Logic Units
- 14-bit Analog-to-Digital Converter with integrated multiplexer, voltage reference, temperature sensor, channel sequencer, and direct-to-XXRAM data transfer
- Two Analog Comparators
- 16-bit CRC Unit
- AEC-Q100 qualified (pending)

In addition to these features, each part number in the EFM8LB1 family has a set of features that vary across the product line. The product selection guide shows the features available on each family member.

Table 2.1. Product Selection Guide

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Voltage DACs	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8LB12F64E-A-QFN32	64	4352	29	20	4	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB12F64E-A-QFP32	64	4352	28	20	4	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB12F64E-A-QFN24	64	4352	20	12	4	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB12F64E-A-QSOP24	64	4352	21	13	4	6	7	Yes	-40 to +105 °C	QSOP24

## Timers (Timer 0, Timer 1, Timer 2, Timer 3, Timer 4, and Timer 5)

Several counter/timers are included in the device: two are 16-bit counter/timers compatible with those found in the standard 8051, and the rest are 16-bit auto-reload timers for timing peripherals or for general purpose use. These timers can be used to measure time intervals, count external events and generate periodic interrupt requests. Timer 0 and Timer 1 are nearly identical and have four primary modes of operation. The other timers offer both 16-bit and split 8-bit timer functionality with auto-reload and capture capabilities.

Timer 0 and Timer 1 include the following features:

- Standard 8051 timers, supporting backwards-compatibility with firmware and hardware.
- Clock sources include SYSCLK, SYSCLK divided by 12, 4, or 48, the External Clock divided by 8, or an external pin.
- 8-bit auto-reload counter/timer mode
- 13-bit counter/timer mode
- 16-bit counter/timer mode
- Dual 8-bit counter/timer mode (Timer 0)

Timer 2, Timer 3, Timer 4, and Timer 5 are 16-bit timers including the following features:

- Clock sources for all timers include SYSCLK, SYSCLK divided by 12, or the External Clock divided by 8
- LFOSC0 divided by 8 may be used to clock Timer 3 and Timer 4 in active or suspend/snooze power modes
- Timer 4 is a low-power wake source, and can be chained together with Timer 3
- 16-bit auto-reload timer mode
- Dual 8-bit auto-reload timer mode
- External pin capture
- LFOSC0 capture
- Comparator 0 capture
- Configurable Logic output capture

## Watchdog Timer (WDT0)

The device includes a programmable watchdog timer (WDT) running off the low-frequency oscillator. A WDT overflow forces the MCU into the reset state. To prevent the reset, the WDT must be restarted by application software before overflow. If the system experiences a software or hardware malfunction preventing the software from restarting the WDT, the WDT overflows and causes a reset. Following a reset, the WDT is automatically enabled and running with the default maximum time interval. If needed, the WDT can be disabled by system software or locked on to prevent accidental disabling. Once locked, the WDT cannot be disabled until the next system reset. The state of the RST pin is unaffected by this reset.

The Watchdog Timer has the following features:

- Programmable timeout interval
- Runs from the low-frequency oscillator
- Lock-out feature to prevent any modification until a system reset

## 3.6 Communications and Other Digital Peripherals

### Universal Asynchronous Receiver/Transmitter (UART0)

UART0 is an asynchronous, full duplex serial port offering modes 1 and 3 of the standard 8051 UART. Enhanced baud rate support allows a wide range of clock sources to generate standard baud rates. Received data buffering allows UART0 to start reception of a second incoming data byte before software has finished reading the previous data byte.

The UART module provides the following features:

- Asynchronous transmissions and receptions
- Baud rates up to SYSCLK/2 (transmit) or SYSCLK/8 (receive)
- 8- or 9-bit data
- Automatic start and stop generation
- Single-byte buffer on transmit and receive

## I2C Slave (I2CSLAVE0)

The I2C Slave interface is a 2-wire, bidirectional serial bus that is compatible with the I2C Bus Specification 3.0. It is capable of transferring in high-speed mode (HS-mode) at speeds of up to 3.4 Mbps. Firmware can write to the I2C interface, and the I2C interface can autonomously control the serial transfer of data. The interface also supports clock stretching for cases where the core may be temporarily prohibited from transmitting a byte or processing a received byte during an I2C transaction. This module operates only as an I2C slave device.

The I2C module includes the following features:

- Standard (up to 100 kbps), Fast (400 kbps), Fast Plus (1 Mbps), and High-speed (3.4 Mbps) transfer speeds
- Support for slave mode only
- Clock low extending (clock stretching) to interface with faster masters
- Hardware support for 7-bit slave address recognition
- Hardware support for multiple slave addresses with the option to save the matching address in the receive FIFO

## 16-bit CRC (CRC0)

The cyclic redundancy check (CRC) module performs a CRC using a 16-bit polynomial. CRC0 accepts a stream of 8-bit data and posts the 16-bit result to an internal register. In addition to using the CRC block for data manipulation, hardware can automatically CRC the flash contents of the device.

The CRC module is designed to provide hardware calculations for flash memory verification and communications protocols. The CRC module supports the standard CCITT-16 16-bit polynomial (0x1021), and includes the following features:

- Support for CCITT-16 polynomial
- Byte-level bit reversal
- Automatic CRC of flash contents on one or more 256-byte blocks
- Initial seed selection of 0x0000 or 0xFFFF

## Configurable Logic Units (CLU0, CLU1, CLU2, and CLU3)

The Configurable Logic block consists of multiple Configurable Logic Units (CLUs). CLUs are flexible logic functions which may be used for a variety of digital functions, such as replacing system glue logic, aiding in the generation of special waveforms, or synchronizing system event triggers.

- Four configurable logic units (CLUs), with direct-pin and internal logic connections
- Each unit supports 256 different combinatorial logic functions (AND, OR, XOR, muxing, etc.) and includes a clocked flip-flop for synchronous operations
- Units may be operated synchronously or asynchronously
- May be cascaded together to perform more complicated logic functions
- Can operate in conjunction with serial peripherals such as UART and SPI or timing peripherals such as timers and PCA channels
- Can be used to synchronize and trigger multiple on-chip resources (ADC, DAC, Timers, etc.)
- Asynchronous output may be used to wake from low-power states

## 3.7 Analog

### 14/12/10-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 14-, 12-, and 10-bit modes, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

- Up to 20 external inputs
- Single-ended 14-bit, 12-bit and 10-bit modes
- Supports an output update rate of up to 1 Msps in 12-bit mode
- Channel sequencer logic with direct-to-XDATA output transfers
- Operation in a low power mode at lower conversion speeds
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer and configurable logic sources
- Output data window comparator allows automatic range checking
- Support for output data accumulation
- Conversion complete and window compare interrupts supported
- Flexible output data formatting
- Includes a fully-internal fast-settling 1.65 V reference and an on-chip precision 2.4 / 1.2 V reference, with support for using the supply as the reference, an external reference and signal ground
- Integrated factory-calibrated temperature sensor

### 12-Bit Digital-to-Analog Converters (DAC0, DAC1, DAC2, DAC3)

The DAC modules are 12-bit Digital-to-Analog Converters with the capability to synchronize multiple outputs together. The DACs are fully configurable under software control. The voltage reference for the DACs is selectable between internal and external reference sources.

- Voltage output with 12-bit performance
- Hardware conversion trigger, selectable between software, external I/O and internal timer and configurable logic sources
- Outputs may be configured to persist through reset and maintain output state to avoid system disruption
- Multiple DAC outputs can be synchronized together
- DAC pairs (DAC0 and 1 or DAC2 and 3) support complementary output waveform generation
- Outputs may be switched between two levels according to state of configurable logic / PWM input trigger
- Flexible input data formatting
- Supports references from internal supply, on-chip precision reference, or external VREF pin

### Low Current Comparators (CMP0, CMP1)

An analog comparator is used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator includes the following features:

- Up to 10 (CMP0) or 9 (CMP1) external positive inputs
- Up to 10 (CMP0) or 9 (CMP1) external negative inputs
- Additional input options:
  - Internal connection to LDO output
  - Direct connection to GND
  - Direct connection to VDD
  - Dedicated 6-bit reference DAC
- Synchronous and asynchronous outputs can be routed to pins via crossbar
- Programmable hysteresis between 0 and  $\pm 20$  mV
- Programmable response time
- Interrupts generated on rising, falling, or both edges
- PWM output kill feature

#### 4.1.4 Flash Memory

**Table 4.4. Flash Memory**

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Write Time <sup>1,2</sup>	$t_{\text{WRITE}}$	One Byte, $F_{\text{SYSCLK}} = 24.5 \text{ MHz}$	19	20	21	$\mu\text{s}$
Erase Time <sup>1,2</sup>	$t_{\text{ERASE}}$	One Page, $F_{\text{SYSCLK}} = 24.5 \text{ MHz}$	5.2	5.35	5.5	ms
$V_{\text{DD}}$ Voltage During Programming <sup>3</sup>	$V_{\text{PROG}}$		2.2	—	3.6	V
Endurance (Write/Erase Cycles)	$N_{\text{WE}}$		20k	100k	—	Cycles

**Note:**

1. Does not include sequencing time before and after the write/erase operation, which may be multiple SYSCLK cycles.
2. The internal High-Frequency Oscillator 0 has a programmable output frequency, which is factory programmed to 24.5 MHz. If user firmware adjusts the oscillator speed, it must be between 22 and 25 MHz during any flash write or erase operation. It is recommended to write the HFO0CAL register back to its reset value when writing or erasing flash.
3. Flash can be safely programmed at any voltage above the supply monitor threshold ( $V_{\text{VDDM}}$ ).
4. Data Retention Information is published in the Quarterly Quality and Reliability Report.

#### 4.1.5 Power Management Timing

**Table 4.5. Power Management Timing**

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Idle Mode Wake-up Time	$t_{\text{IDLEWK}}$		2	—	3	SYSCLKs
Suspend Mode Wake-up Time	$t_{\text{SUS-}}t_{\text{PENDWK}}$	$\text{SYSCLK} = \text{HFOSC0}$ $\text{CLKDIV} = 0x00$	—	170	—	ns
Snooze Mode Wake-up Time	$t_{\text{SLEEPWK}}$	$\text{SYSCLK} = \text{HFOSC0}$ $\text{CLKDIV} = 0x00$	—	12	—	$\mu\text{s}$

## 4.1.6 Internal Oscillators

Table 4.6. Internal Oscillators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
High Frequency Oscillator 0 (24.5 MHz)						
Oscillator Frequency	$f_{\text{HFOSC0}}$	Full Temperature and Supply Range	24	24.5	25	MHz
Power Supply Sensitivity	$\text{PSS}_{\text{HFOSC0}}$	$T_A = 25^\circ\text{C}$	—	0.5	—	%/V
Temperature Sensitivity	$\text{TS}_{\text{HFOSC0}}$	$V_{\text{DD}} = 3.0\text{ V}$	—	40	—	ppm/°C
High Frequency Oscillator 1 (72 MHz)						
Oscillator Frequency	$f_{\text{HFOSC1}}$	Full Temperature and Supply Range	70.5	72	73.5	MHz
Power Supply Sensitivity	$\text{PSS}_{\text{HFOSC1}}$	$T_A = 25^\circ\text{C}$	—	TBD	—	%/V
Temperature Sensitivity	$\text{TS}_{\text{HFOSC1}}$	$V_{\text{DD}} = 3.0\text{ V}$	—	TBD	—	ppm/°C
Low Frequency Oscillator (80 kHz)						
Oscillator Frequency	$f_{\text{LFOSC}}$	Full Temperature and Supply Range	75	80	85	kHz
Power Supply Sensitivity	$\text{PSS}_{\text{LFOSC}}$	$T_A = 25^\circ\text{C}$	—	0.05	—	%/V
Temperature Sensitivity	$\text{TS}_{\text{LFOSC}}$	$V_{\text{DD}} = 3.0\text{ V}$	—	65	—	ppm/°C

## 4.1.7 External Clock Input

Table 4.7. External Clock Input

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency (at EXTCLK pin)	$f_{\text{CMOS}}$		0	—	50	MHz
External Input CMOS Clock High Time	$t_{\text{CMOSH}}$		9	—	—	ns
External Input CMOS Clock Low Time	$t_{\text{CMOSL}}$		9	—	—	ns

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Power Supply Rejection Ratio	PSRR <sub>ADC</sub>		—	TBD	—	dB
DC Performance						
Integral Nonlinearity	INL	14 Bit Mode	—	TBD	—	LSB
		12 Bit Mode	-1.4	TBD	+1.4	LSB
		10 Bit Mode	—	TBD	—	LSB
Differential Nonlinearity (Guaranteed Monotonic)	DNL	14 Bit Mode	—	TBD	—	LSB
		12 Bit Mode	—	TBD	0.9	LSB
		10 Bit Mode	—	TBD	—	LSB
Offset Error	E <sub>OFF</sub>	14 Bit Mode	—	TBD	—	LSB
		12 Bit Mode	-2	TBD	2	LSB
		10 Bit Mode	—	TBD	—	LSB
Offset Temperature Coefficient	TC <sub>OFF</sub>		—	TBD	—	LSB/°C
Slope Error	E <sub>M</sub>	14 Bit Mode	—	TBD	—	%
		12 Bit Mode	—	TBD	TBD	%
		10 Bit Mode	—	TBD	—	%
Dynamic Performance 10 kHz Sine Wave Input 1 dB below full scale, Max throughput, using AGND pin						
Signal-to-Noise	SNR	14 Bit Mode	—	TBD	—	dB
		12 Bit Mode	TBD	TBD	—	dB
		10 Bit Mode	—	TBD	—	dB
Signal-to-Noise Plus Distortion	SNDR	14 Bit Mode	—	TBD	—	dB
		12 Bit Mode	TBD	TBD	—	dB
		10 Bit Mode	—	TBD	—	dB
Total Harmonic Distortion (Up to 5th Harmonic)	THD	14 Bit Mode	—	TBD	—	dB
		12 Bit Mode	—	TBD	—	dB
		10 Bit Mode	—	TBD	—	dB
Spurious-Free Dynamic Range	SFDR	14 Bit Mode	—	TBD	—	dB
		12 Bit Mode	—	TBD	—	dB
		10 Bit Mode	—	TBD	—	dB

**Note:**

1. This time is equivalent to four periods of a clock running at 18 MHz + 2%.

2. Conversion Time does not include Tracking Time. Total Conversion Time is:

$$\text{Total Conversion Time} = [\text{RPT} \times (\text{ADTK} + \text{NUMBITS} + 1) \times \text{T}(\text{SARCLK})] + (\text{T}(\text{ADCCLK}) \times 4)$$

where RPT is the number of conversions represented by the ADRPT field and ADCCLK is the clock selected for the ADC.

3. Absolute input pin voltage is limited by the V<sub>IO</sub> supply.



#### 4.1.10 Voltage Reference

Table 4.10. Voltage Reference

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Internal Fast Settling Reference						
Output Voltage (Full Temperature and Supply Range)	$V_{\text{REFFS}}$		1.62	1.65	1.68	V
Temperature Coefficient	$TC_{\text{REFFS}}$		—	50	—	ppm/°C
Turn-on Time	$t_{\text{REFFS}}$		—	—	1.5	μs
Power Supply Rejection	$PSRR_{\text{REFFS}}$		—	400	—	ppm/V
On-chip Precision Reference						
Valid Supply Range	$V_{\text{DD}}$	1.2 V Output	2.2	—	3.6	V
		2.4 V Output	2.7	—	3.6	V
Output Voltage	$V_{\text{REFP}}$	1.2 V Output, T = 25 °C	TBD	1.2	TBD	V
		2.4 V Output, T = 25 °C	TBD	2.4	TBD	V
Turn-on Time, settling to 0.5 LSB	$t_{\text{VREFP}}$	4.7 μF tantalum + 0.1 μF ceramic bypass on VREF pin	—	3	—	ms
		0.1 μF ceramic bypass on VREF pin	—	100	—	μs
Load Regulation	$LR_{\text{VREFP}}$	Load = 0 to 200 μA to GND	—	TBD	—	μV/μA
Load Capacitor	$C_{\text{VREFP}}$	Load = 0 to 200 μA to GND	0.1	—	—	μF
Short-circuit current	$ISC_{\text{VREFP}}$		—	—	8	mA
Power Supply Rejection	$PSRR_{\text{VREFP}}$		—	TBD	—	ppm/V
External Reference						
Input Current	$I_{\text{EXTREF}}$	ADC Sample Rate = 1 Msps; VREF = 3.0 V	—	5	—	μA

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Negative Hysteresis Mode 3 (CPMD = 11)	HYS <sub>CP-</sub>	CPHYN = 00	—	-1.5	—	mV
		CPHYN = 01	—	-4	—	mV
		CPHYN = 10	—	-8	—	mV
		CPHYN = 11	—	-16	—	mV
Input Range (CP+ or CP-)	V <sub>IN</sub>		-0.25	—	V <sub>IO</sub> +0.25	V
Input Pin Capacitance	C <sub>CP</sub>		—	7.5	—	pF
Internal Reference DAC Resolution	N <sub>bits</sub>		6			bits
Common-Mode Rejection Ratio	CMRR <sub>CP</sub>		—	70	—	dB
Power Supply Rejection Ratio	PSRR <sub>CP</sub>		—	72	—	dB
Input Offset Voltage	V <sub>OFF</sub>	T <sub>A</sub> = 25 °C	-10	0	10	mV
Input Offset Tempco	TC <sub>OFF</sub>		—	3.5	—	μV/°

#### 4.1.14 Configurable Logic

**Table 4.14. Configurable Logic**

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Propagation Delay	t <sub>DLY</sub>	Through single CLU	TBD	—	TBD	ns
Clocking Frequency	F <sub>CLK</sub>	1 or 2 CLUs Cascaded	—	—	73.5	MHz
		3 or 4 CLUs Cascaded	—	—	36.75	MHz

## 4.2 Thermal Conditions

**Table 4.16. Thermal Conditions**

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance	$\theta_{JA}$	QFN24 Packages	—	TBD	—	°C/W
		QFN32 Packages	—	TBD	—	°C/W
		QFP32 Packages	—	80	—	°C/W
		QSOP24 Packages	—	65	—	°C/W
<b>Note:</b> 1. Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.						

## 4.3 Absolute Maximum Ratings

Stresses above those listed in [Table 4.17 Absolute Maximum Ratings on page 27](#) may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at <http://www.silabs.com/support/quality/pages/default.aspx>.

**Table 4.17. Absolute Maximum Ratings**

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	$T_{BIAS}$		-55	125	°C
Storage Temperature	$T_{STG}$		-65	150	°C
Voltage on VDD	$V_{DD}$		GND-0.3	4.2	V
Voltage on VIO <sup>2</sup>	$V_{IO}$		GND-0.3	$V_{DD}+0.3$	V
Voltage on I/O pins or RSTb, excluding P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	$V_{IN}$	$V_{IO} > \text{TBD V}$	GND-0.3	TBD	V
		$V_{IO} < \text{TBD V}$	GND-0.3	TBD	V
Voltage on P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	$V_{IN}$		GND-0.3	$V_{DD}+0.3$	V
Total Current Sunk into Supply Pin	$I_{VDD}$		—	400	mA
Total Current Sourced out of Ground Pin	$I_{GND}$		400	—	mA
Current Sourced or Sunk by any I/O Pin or RSTb	$I_{IO}$		-100	100	mA
<b>Note:</b> 1. Exposure to maximum rating conditions for extended periods may affect device reliability. 2. In certain package configurations, the VIO and VDD supplies are bonded to the same pin.					

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
18	P1.7	Multifunction I/O	Yes	P1MAT.7 CLU0B.15 CLU1B.13 CLU2A.13	ADC0.13 CMP0P.9 CMP0N.9
19	P1.6	Multifunction I/O	Yes	P1MAT.6 CLU0A.15 CLU1B.12 CLU2A.12	ADC0.12
20	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU0B.14 CLU1A.13 CLU2B.13 CLU3B.11	ADC0.11
21	P1.4	Multifunction I/O	Yes	P1MAT.4 CLU0A.14 CLU1A.12 CLU2B.12 CLU3B.10	ADC0.10
22	P1.3	Multifunction I/O	Yes	P1MAT.3 CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	ADC0.9
23	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12 CLU3B.13	ADC0.8 CMP0P.8 CMP0N.8
24	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.12	ADC0.7 CMP0P.7 CMP0N.7

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
30	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3 CLU0B.9 CLU2B.10 CLU3A.9	XTAL2
31	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2 CLU0OUT CLU0A.9 CLU2B.8 CLU3A.8	XTAL1 ADC0.1 CMP0P.1 CMP0N.1
32	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1 CLU0B.8 CLU2A.9 CLU3B.9	ADC0.0 CMP0P.0 CMP0N.0 AGND

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
12	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU2OUT CLU0B.14 CLU1A.13 CLU2B.13 CLU3B.11	ADC0.10 CMP1P.4 CMP1N.4
13	P1.4	Multifunction I/O	Yes	P1MAT.4 I2C0_SCL CLU0A.14 CLU1A.12 CLU2B.12 CLU3B.10	ADC0.9 CMP1P.3 CMP1N.3
14	P1.3	Multifunction I/O	Yes	P1MAT.3 I2C0_SDA CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	CMP1P.2 CMP1N.2
15	GND	Ground			
16	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12 CLU3B.13	ADC0.8
17	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.12	ADC0.7
18	P1.0	Multifunction I/O	Yes	P1MAT.0 CLU0A.12 CLU1A.10 CLU2A.10	ADC0.6

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
19	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7 CLU1OUT CLU0B.11 CLU1B.9 CLU3A.11	ADC0.5 CMP0P.5 CMP0N.5 CMP1P.1 CMP1N.1
20	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6 CLU0A.11 CLU1B.8 CLU3A.10	ADC0.4 CMP0P.4 CMP0N.4 CMP1P.0 CMP1N.0
21	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX CLU0B.10 CLU1A.9	ADC0.3 CMP0P.3 CMP0N.3
22	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4 UART0_TX CLU0A.10 CLU1A.8	ADC0.2 CMP0P.2 CMP0N.2
23	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3 CLU0B.9 CLU2B.10 CLU3A.9	XTAL2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
2	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2 CLU0OUT CLU0A.9 CLU2B.8 CLU3A.8	XTAL1 ADC0.1 CMP0P.1 CMP0N.1
3	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1 CLU0B.8 CLU2A.9 CLU3B.9	ADC0.0 CMP0P.0 CMP0N.0 AGND
4	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
5	GND	Ground			
6	VDD / VIO	Supply Power Input			
7	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
8	P3.0 / C2D	Multifunction I/O / C2 Debug Data			
9	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	DAC3
10	P2.2	Multifunction I/O	Yes	P2MAT.2 CLU1A.15 CLU2B.14 CLU3A.14	DAC2



Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
11	P2.1	Multifunction I/O	Yes	P2MAT.1 CLU1B.14 CLU2A.15 CLU3B.15	DAC1
12	P2.0	Multifunction I/O	Yes	P2MAT.0 CLU1A.14 CLU2A.14 CLU3B.14	DAC0
13	P1.7	Multifunction I/O	Yes	P1MAT.7 CLU0B.15 CLU1B.13 CLU2A.13	ADC0.12 CMP1P.6 CMP1N.6
14	P1.6	Multifunction I/O	Yes	P1MAT.6 CLU3OUT CLU0A.15 CLU1B.12 CLU2A.12	ADC0.11 CMP1P.5 CMP1N.5
15	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU2OUT CLU0B.14 CLU1A.13 CLU2B.13 CLU3B.11	ADC0.10 CMP1P.4 CMP1N.4
16	P1.4	Multifunction I/O	Yes	P1MAT.4 I2C0_SCL CLU0A.14 CLU1A.12 CLU2B.12 CLU3B.10	ADC0.9 CMP1P.3 CMP1N.3
17	P1.3	Multifunction I/O	Yes	P1MAT.3 I2C0_SDA CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	CMP1P.2 CMP1N.2

## 7.2 QFN32 PCB Land Pattern

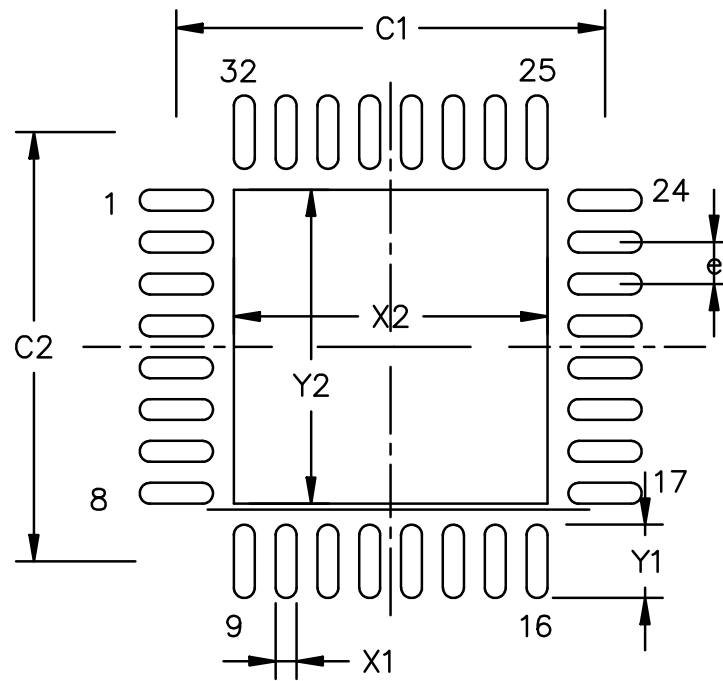


Figure 7.2. QFN32 PCB Land Pattern Drawing

Table 7.2. QFN32 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	—	4.00
C2	—	4.00
X1	—	0.2
X2	—	2.8
Y1	—	0.75
Y2	—	2.8
e	—	0.4

## 9.2 QFN24 PCB Land Pattern

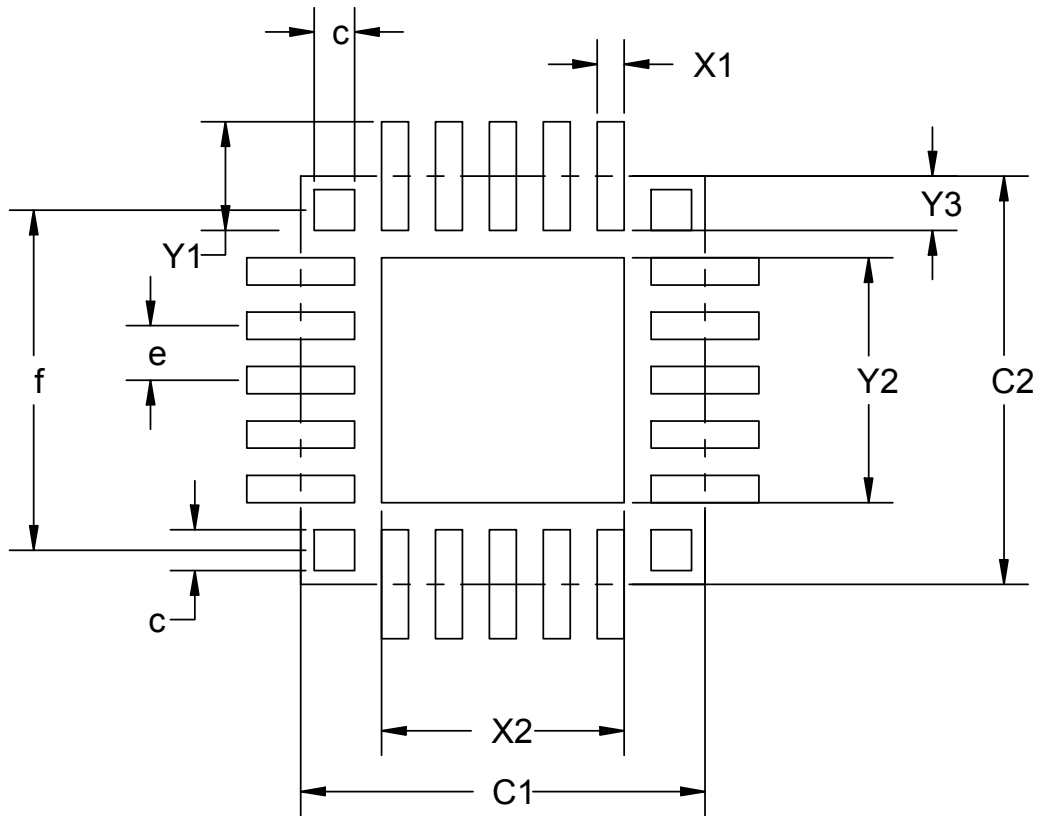


Figure 9.2. QFN24 PCB Land Pattern Drawing

Table 9.2. QFN24 PCB Land Pattern Dimensions

Dimension	Min	Max
C1		3.00
C2		3.00
e		0.4 REF
X1		0.20
X2		1.80
Y1		0.80
Y2		1.80
Y3		0.4
f		2.50 REF
c	0.25	0.35

## 10. QSOP24 Package Specifications

### 10.1 QSOP24 Package Dimensions

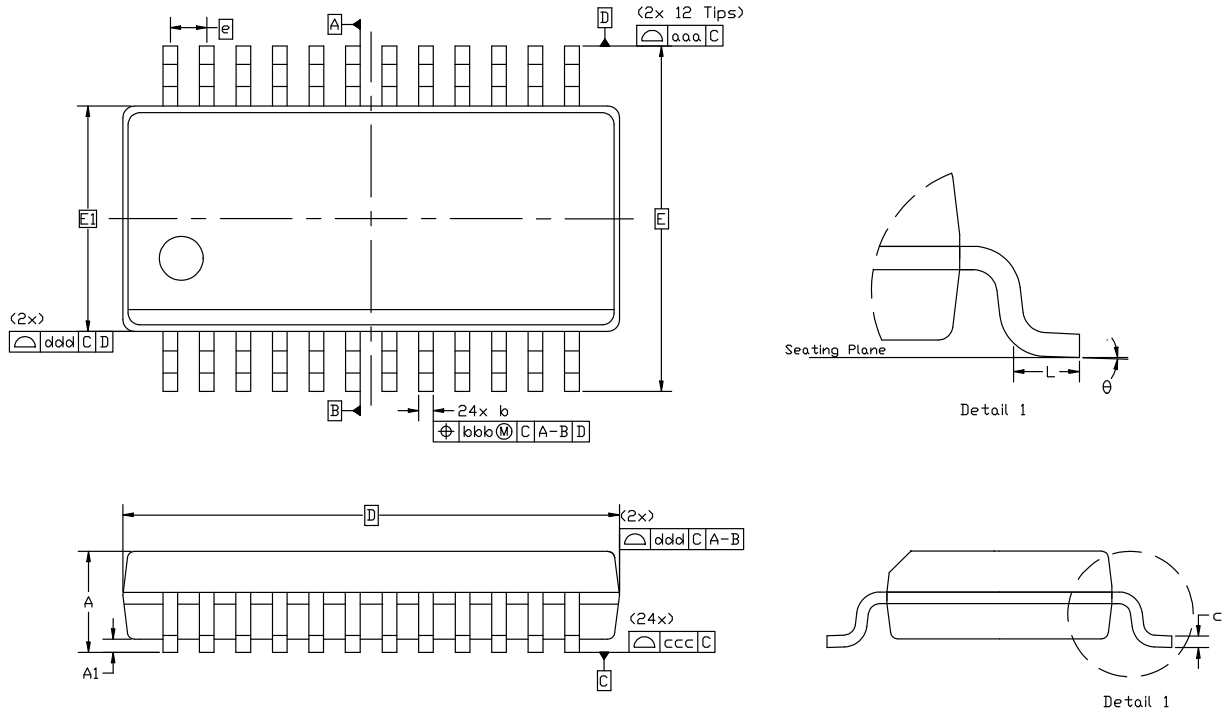


Figure 10.1. QSOP24 Package Drawing

Table 10.1. QSOP24 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.75
A1	0.10	—	0.25
b	0.20	—	0.30
c	0.10	—	0.25
D	8.65 BSC		
E	6.00 BSC		
E1	3.90 BSC		
e	0.635 BSC		
L	0.40	—	1.27
theta	0°	—	8°

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